

## AK Trench-FS IGBT

### Features

- Trench FS technology
- Low  $V_{CE(sat)}$
- Low switching loss
- Easy paralleling

### Application

- Photovoltaic converters
- Mid to high range switching frequency converters
- UPS

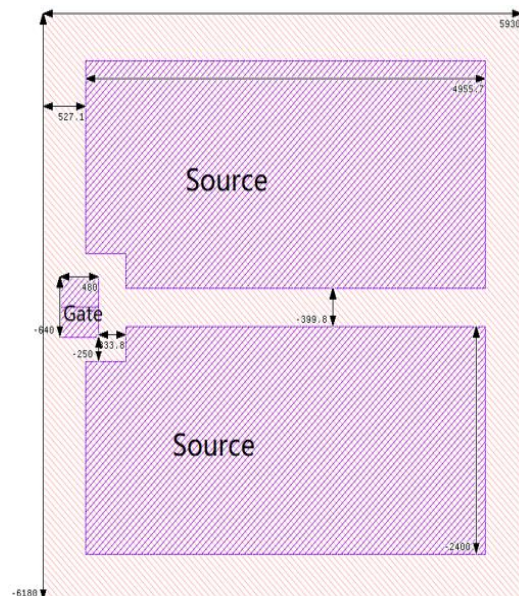
Wafer Size (inch)	8
Chip Size with scribe (mm2)	6.09 x 6.34
Wafer Thickness (um)	70±5
Gate PAD Size (mm2)	0.48 x 0.64
Emitter PAD Size (mm2)	4.955 x 2.4
Top Metal	AlCu
Top Metal Thickness (µm)	4
Back Metal	Al/Ti/Ni/Ag
Scribe Line (µm)	80
Passivation	Polyimide
Gross Die	688
Recommended Storage Environment	Store in original container, in dry nitrogen, <3months at an ambient temperature of 23±3°C

### 650V100A Trench FS IGBT

Parameter	Value	Unit
$V_{CE}$	650	V
$I_c$	100	A
$V_{CE(sat)}$ at $I_c=100A$ (Wafer level test)	1.4	V

Unit: um

Die Size Without 80um scribe line



**Maximum Ratings (T<sub>j</sub>=25°C, unless otherwise specified)**

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V <sub>CE</sub>	650	V
Gate-emitter voltage	V <sub>GE</sub>	+/-20	V
DC collector current	I <sub>C</sub>		
T <sub>j</sub> =25°C		200	A
T <sub>j</sub> =100°C		100	A
Pulsed collector current	I <sub>CM</sub>	400	A
Junction temperature range	T <sub>vj</sub>	-40~+175	°C
sOperating junction temperature	T <sub>vjop</sub>	-40~+150	°C

**Electrical Characteristics at T<sub>j</sub>=25°C (unless otherwise specified)**

Parameter	Symbol	Conditions	Value			Unit
			Min.	Typ.	Max.	
<b>Static Characteristic (Test on wafer)</b>						
Collector-emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> =0V, I <sub>C</sub> =0.1mA	650	-	-	V
Gate-emitter threshold voltage	V <sub>GE(th)</sub>	I <sub>C</sub> =1mA, V <sub>CE</sub> =V <sub>GE</sub>	4.1	5.1	6.1	V
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	V <sub>GE</sub> =15V, I <sub>C</sub> =100A	-	1.4	1.7	V
Gate leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V, V <sub>GE</sub> =+/-20V	-	-	200	nA
Collector leakage current	I <sub>CES</sub>	V <sub>CE</sub> =650V, V <sub>GE</sub> =0V	-	-	50	uA